

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Semiconductor devices – Mechanical and climatic test methods –
Part 32: Flammability of plastic-encapsulated devices (externally induced)**

**Dispositifs à semiconducteurs – Méthodes d'essais mécaniques et climatiques –
Partie 32: Inflammabilité des dispositifs à encapsulation plastique (cas d'une
cause extérieure d'inflammation)**

[IEC 60749-32:2002](https://standards.iteh.ai/)

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES –
MECHANICAL AND CLIMATIC TEST METHODS –****Part 32: Flammability of plastic-encapsulated devices
(externally induced)**

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A vertical line in the margin shows where the base publication has been modified by amendment 1. Additions and deletions are displayed in red, with deletions being struck through.

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INTRODUCTION

Activity within IEC technical committee 47, working group 2, includes the generation, coordination and review of climatic, electrical (of which only ESD, latch-up and electrical conditions for life tests are considered), mechanical test methods, and associated inspection techniques needed to assess the quality and reliability of the design and manufacture of semiconductor products and processes.

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